

ECE 656: Week 10 References

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There are several good books and review articles about measuring the near-equilibrium transport parameters.

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Kasper A. Borup, Johannes de Boor, Heng Wang, Fivos Drymiotis, Franck Gascoin, Xun Shi, Lidong Chen, Mikhail I. Fedorov, Eckhard Muller, Bo B. Iversen, and G. Jeffrey Snyder, "Measuring thermoelectric transport properties of Materials," *Energy & Environmental Science*, **8**, 423–435, 2015.